# **Resource Summary Report**

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# **FEI Helios G4 UX**

RRID:SCR\_021773

Type: Tool

### **Proper Citation**

FEI Helios G4 UX (RRID:SCR\_021773)

#### Resource Information

URL: http://www.mcpf.hkust.edu.hk/service.php?id=PE022

**Proper Citation:** FEI Helios G4 UX (RRID:SCR\_021773)

**Description:** Dual beam FIB/FESEM system, containing both focused Ga plus ion beam and ultra high resolution field emission scanning electron column and their combined use. Dual beam focused ion beam scanning electron microscope for nanofabrication.

Synonyms: Helios G4 UX

**Resource Type:** instrument resource

**Keywords:** FIB, SEM, nanofabrication, dual beam, focused ion beam, scanning electron

microscope, USEDit

**Funding:** 

Availability: Commercially available

Resource Name: FEI Helios G4 UX

Resource ID: SCR\_021773

Alternate IDs: Model Number FEI Helios G4 UX

**Record Creation Time:** 20220129T080357+0000

Record Last Update: 20250420T015133+0000

### Ratings and Alerts

No rating or validation information has been found for FEI Helios G4 UX.

No alerts have been found for FEI Helios G4 UX.

## **Data and Source Information**

Source: SciCrunch Registry

## **Usage and Citation Metrics**

We found 1 mentions in open access literature.

**Listed below are recent publications.** The full list is available at NIF.

Ichikawa T, et al. (2023) Protocol for live imaging of intracellular nanoscale structures using atomic force microscopy with nanoneedle probes. STAR protocols, 4(3), 102468.